

# INSTRUCTION MANUAL R47252A PERSONALITY KIT

MANUAL NUMBER OEA00 9006

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Preface

#### **PREFACE**

Note the following description in this manual.

Device : Means the R47252A personality kit.

Main unit : Means logic analyzer TR4726 (on which the R47252A is

installed).

SUT : Abbreviation of System Under Test.

68000/68010 : Motorola's microprocessor

 $\mu P$  is an abbreviation of microprocessor.



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1.1 Outline

#### 1. OVERVIEW

#### 1.1 Outline

The R47252A personality kit for 68000/68010 is plugged in the TR4726 logic analyzer (opt06: Synchronous analysis module is also used) to analyze the state. The following three types of analyzers can be used by combination of the kit and timing analysis module (option).

- (1) Timing Only Analyzer
- (2) State Analyzer
- (3) S & T (state and timing) Analyzer

This manual mainly explains how to operate the state analyzer. For the detail of the TR4726, refer to the TR4726 Logic Analyzer Operation Manual.

1.2 Outline of Product

#### 1.2 Outline of Product

The R47252A features as follows.

- (1) Emulates the queue in the CPU of 68000/68010 by hardware. So, it analyzes easily the execution requiring complicated prefetch.
- (2) Uses 68000/68010 mnemonic in addition to values to analyze fetched data, so the rate of state analysis can be improved.
- (3) Fetches data by dedicated hardware, and enables the high level analysis by relatively-small probe.
- (4) Defines the symbol and code by setting the test condition or analyzing test data. So, the rate of state analysis can be improved.
- (5) Supports complicated application owing to several trace window conditions or memory resolution (store function) by setting the trace condition.
- (6) Realizes advanced user interface such as disk control regardless of the menu method and disk. This function serves for the energy-saving, standardized, and automatic tests.
- (7) The system disk attached to the R47252A offers most of system software. So, the functions and features of the R47252A can be improved when the system disk is revised.

#### 1.3 Requirements Before Using the R47252A

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#### 1.3.1 Checking External View and Accessories

On receiving the R47252A, inspect the external view and check whether any cracks or damage has occured during transportation.

Then, check the standard accessories according to Table 1-1 and verify each quantity and specification.

If any cracks or damage is found or if some accessories are missing, contact the sales division or agency nearest your place of business. Address and telephone numbers are listed at the end of this manual.

Table 1 - 1 Standard Accessary List

Item	Model name	Quantity
Personality board		2
Microprocessor probe	TR14725-20	1
64-pin DIP clip cable	A04725-21	1
64-pin DIP plug cable	A04725-22	1
Probe test adapter	·	1
System software package	P47252-026FJ	1
Blank disk	MF-2DD	1
Disk case		1
Operation manual		1

The blank disk can be purchased separately. Model name: A09502 (a set of 10 disks)

MEMO

2.1 Outline

#### 2. PREPARATION FOR TEST AND PREVIOUS KNOWLEDGE

#### 2.1 Outline

When using the R47252A for the first time, be sure to read this chapter. The chapter explains the preparation work for test and the previous knowledge required to operate the R47252A. It is recommended that you should do the above work and operate the R47252A actually according to the chapter.

#### 2.2 Installing the Personality Board

#### Procedure

- ① Check that the R47252A is powered off.
- ② Remove the machine screw (3mm, +) from the upper cover of R47252A, and remove the cover.
- When the other personality board is installed, remove the board. Marks 1 and 2 are stuck on the slots of the personality board (see Figure 2-1).
- Insert the personality board whose card ejector is marked by 1 into slot 1.
- (5) Insert the personality board whose card ejector is marked by 2 into slot 2. Connect the 50-pin flat cable to the connector in the center of the board.
- 6 Install the upper cover using machine screw as before.

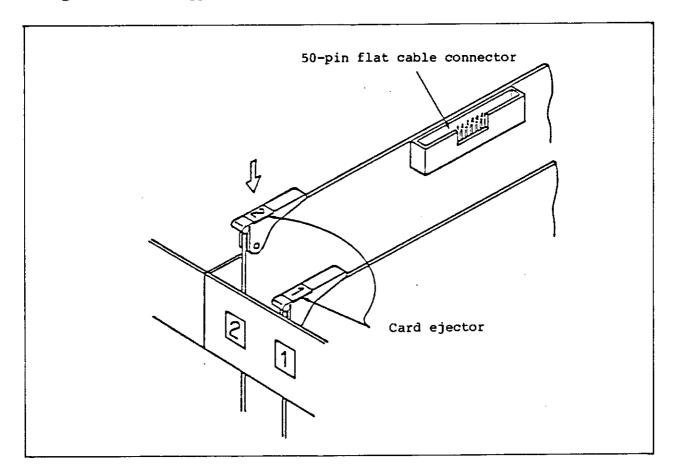


Figure 2 - 1 Mounting the Personality Board

2.3 Connecting the SUT to the Probe

#### 2.3 Connecting the SUT to the Probe

The following explains how to connect the R47252A to the SUT that uses 68000/68010.

#### 2.3.1 Connecting the Microprocessor Probe

The R47252A has the microprocessor probe (TR14725-20) to connect the system under test (SUT) that uses microprocessor 68000 or 68010. This section explains how to connect the probe. Figure 2-2 shows the shape and partial names of the microprocessor probe.

#### (1) Connecting the Microprocessor Probe to the R47252A

As shown below, the microprocessor probe (TR14725-20) has three probe connectors B, C, and D. Connect these connectors to probe slots B, C, and D on the rear of the R47252A. These connectors are locked by screw.

Be sure to power off the R47252A before connecting the microprocessor probe.

- NOTE -

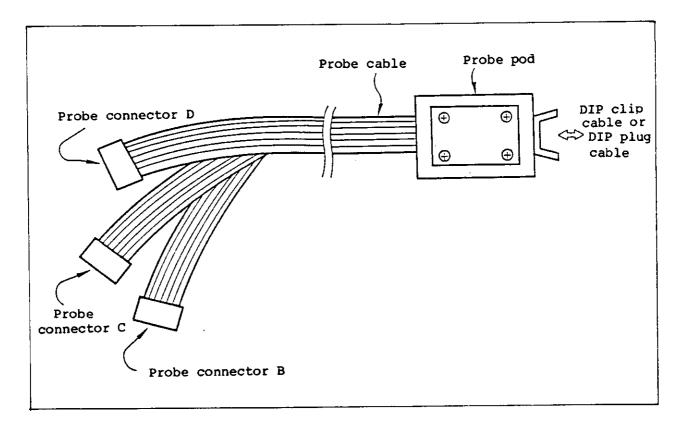


Figure 2 - 2 Shape and Partial Names of Microprocessor Probe

#### 2.3 Connecting the SUT to the Probe

## (2) Connecting the Microprocessor probe to the SUT

Connect the SUT to the microprocessor probe through the 68000 or 68010 microprocessor. The following two methods of connecting can be used. The one uses the DIP clip cable (see Figure 2-3). The other uses the DIP plug cable (see Figure 2-4).

Note: When the microprocessor uses the socket, both methods are enabled. When the microprocessor is soldered, only the DIP clip cable can be used. In both cases, connect pin 1 carefully.

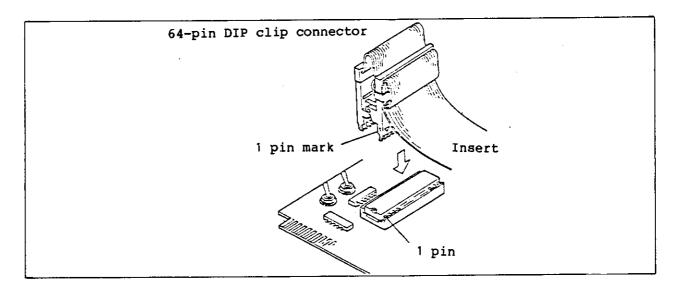


Figure 2 - 3 Using the DIP Clip Cable

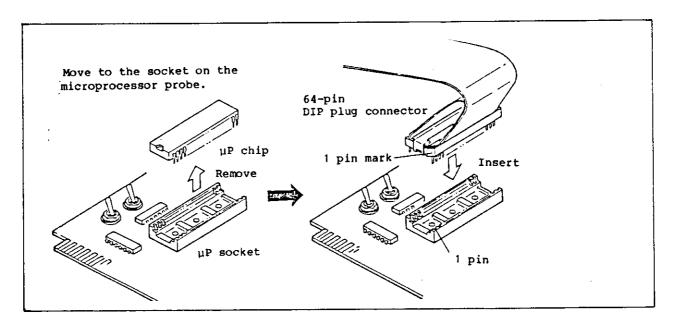


Figure 2 - 4 Using the DIP Plug Cable

3.1 Outline

#### 3. BASIC TEST OPERATION

#### 3.1 Outline

This chapter explains how to operate the TR4726 logic analyzer for a state analyzer.

3.2 Menu Screen Structure

#### 3.2 Menu Screen Structure

The control method according to the menu is used in the TR4726 logic analyzer. The screen having more than one reference menu item is called menu screen. Insert the system disk into the floppy disk drive of the TR4726 and start the TR4726, and the menu screen in Figure 3-1 displayed.

\*\* CONFIGURATION \*\*

\*\* CONFIGURATION \*\*

\*\* CONSINETION OF NODULES

HOUE CURSOR TO SELECT A COMBINATION MODE

1. TIMING ANALYSIS ONLY

2. STATE ANALYSIS ONLY

3. S & T COMBINATION, \*TIMING\* ARMS \*STATE\* (T+S)

4. S & T COMBINATION, \*STATE\* ARMS \*TIMING\* (S+T)

KNOB CURSOR\*\*

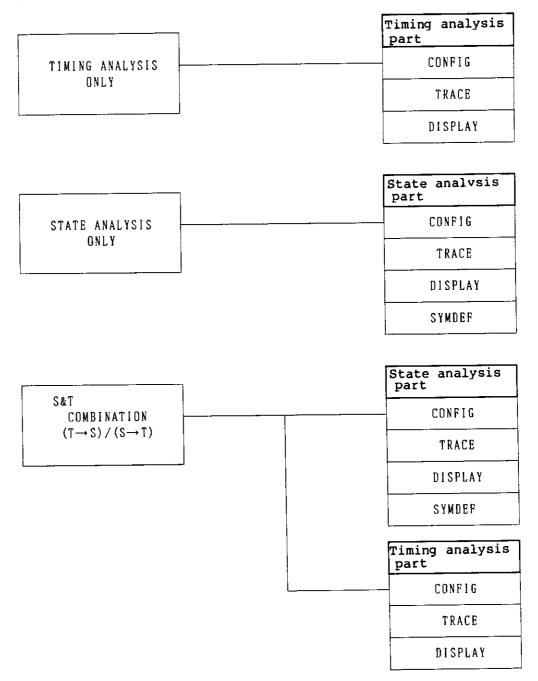
Figure 3 - 1 Start Menu Screen

- TIMING ANALYSIS ONLY: Uses timing analysis part only.
- STATE ANALYSIS ONLY: Uses state analysis part only.
- 3. & 4. S & T COMBINATION : Used for a combination analyzer by state analysis and timing analysis functions.

Move the cursor by knob and press the SELECT key, and the SET UP screen is displayed.

3.2 Menu Screen Structure

The menu screens in modes are configured as follows.



The menu screen of state analysis part in the S & T COMBINATION MODE is  $$^{\text{STATE}}_{\text{TIMING}}$$ 

#### 3.3 Input Channel Structure (CONFIG function)

#### 3.3 Input Channel Structure (CONFIG function)

#### 3.3.1 CONFIG Menu Screen for 68000/68010

CONFIG determines the structure of input part of TR4726 on which the R47252A is installed. Section 2.3.1 explains how to connect the probe to the SUT. This section explains the CONFIG function.

This function levels the electric signals input from the probe of R47252A, samples, and converts them into logical data that is treated easily. It is explained below.

Figure 3-2 shows the menu screen of state analysis part.

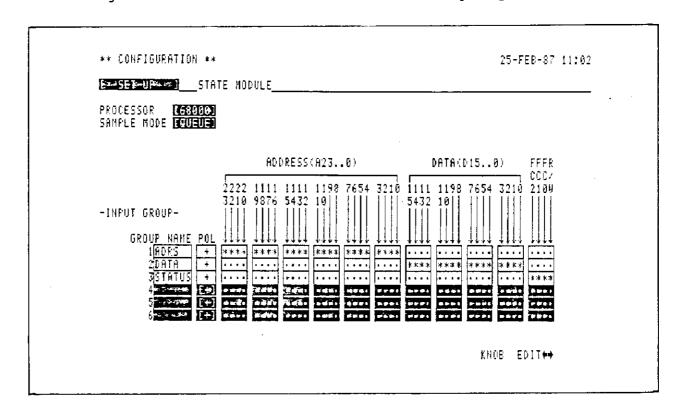


Figure 3 - 2 Menu Screen of State Analysis Part

The symbol with arrow indicates the names of 68000 and 68010 signal pins. The 68000 and 68010 have no signal name A0 (LSB of address bus). Since the odd address is accessed actually, they generates the signal name internally using the UDS and LDS signals to use. The odd address can be used by defining the SYMBOL and CODE, and setting the trace condition.

The following items can be set on the screen (Figure 3-2).

- o PROCESSOR : Selects 68000 and 68010.
- o SAMPLE MODE : Selects QUEUE sample mode and BUS sample mode.

## 3.3 Input Channel Structure (CONFIG function)

The QUEUE sample mode synchronizes with the instruction queue in the 68000 or 68010, and fetches data. The non-executable instruction of prefetched instructions does not fetch data, so it is fit to trace software. The BUS sample mode fetches data output to the bus of 68000 or 68010. The mode fetches the non-executable instruction of fetched instructions. It is fit to see the relation to peripheral equipment.

- POL
- GROUP
- : Specify the polarity + or to fetch the signal.
- : The unit treating several input channels together can be defined as an input GROUP (GROUP). To define the GROUP, determine the name of the GROUP by up to six alphanumeric characters. Specify the input channel belonging to the GROUP by inputting an asterisk. Up to six GROUPs can be specified. Three groups ADRS, DATA, and STATUS of them are already defined in the R47252A and cannot be changed by user. The residual three groups can be defined by user. Already-used input channel cannot be duplicated.

#### 3.4 Setting the Trace Condition (TRACE function)

3.4 Setting the Trace Condition (TRACE function)

TRACE specifies the test mode, and sets the trace condition that is the center of test condition. The main purpose of the trace condition is to focus the trigger as standard to obtain the data part requiring to analyze the SUT from the flow of large quantity of data input from the input channel.

The R47252A can support complicated data flow by combination of S & T function (trigger arming) and several trace window conditions.

3.4.1 Setting the Trace Condition in the State Analysis Part

Press the TRACE menu screen (figure 3-3) is displayed.

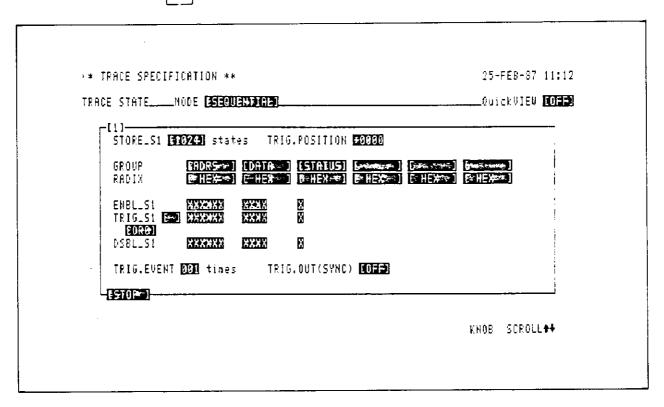


Figure 3 - 3 Initial Menu Screen of TRACE

For the trace mode in the state analysis part, the TRACE TRIG mode and SEQUENTIAL mode can be used. The following shows the initial screen in each mode.

#### 3.4 Setting the Trace Condition (TRACE function)

* TRACE SPECIFICATION **	25-FE8-87 11:
RACE STATEHODE [#9EQUENTIAL]	QuickVIEW <b>EOF</b>
STORE_S1 [31024] states TRIG.POSITION [31	5000
GROUP	HEXXXII E HEXXXII E HEXXXII
ENBL_S1 ENTERN MARK M	}
ECREAL  05BL_51 EXMANNE EXEM M	
TRIG.EVENT DDI times TRIG.OUT(SYNC) [	
[STOP*]	
	KHOB SCROLL <b>+</b> +

Figure 3 - 4 Initial Screen in the SEQUENTIAL Mode

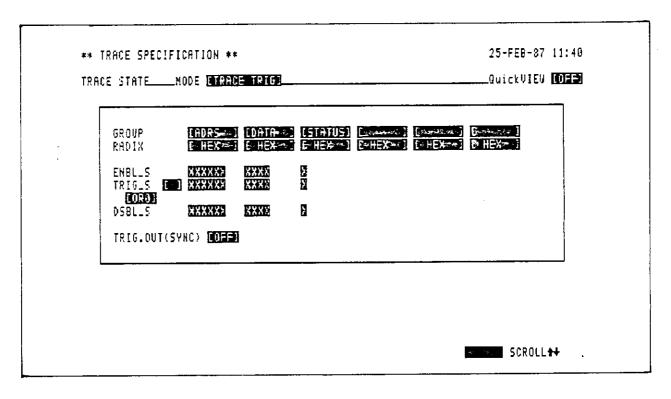


Figure 3 - 5 Initial Screen in TRACE TRIG Mode

## 3.4 Setting the Trace Condition (TRACE function)

MODE TRACE TRIG
MODE SEQUENTIAL

: Only the pattern set by TRIG\_S is traced.

: Data is obtained by combination of up to four trace window conditions and up to four trace window conjunctions.

The SEQUENTIAL mode can set an independent trigger condition in trace windows, and obtains data under its trigger condition.

#### (1) Menu for Trace Window Condition

One trace window condition consists of the store condition, trigger condition, and specification of trigger pulse on/off. In description below, n ranges from 1 to 4.

The store condition (STOREn, TRIG POSITION) specifies the size of trace window n and the trigger point.

• STOREn

: The quantity of acquisition memory (ACQ\_MEM) in the state analysis part is 48 CH. X 1024 states. It can be divided in the direction of depth. As a value, an exponent of 2 (0, 1, to 1024) can be set. If the exponent is 0, data cannot be fetched in memory (the trigger condition is enabled). If it is 1, only the trigger condition is fetched. When several trace windows are used, the store value of trace window 1 must be less than 512. Flexible data can be fetched by combination of the value and trace window conjunction.

#### • TRIG POSITION

: The trigger point in data for trace window n can be set. The range from -3072 to + (store value -1) state (decimal) can be set. When the positive value is set, data prior to the trigger can be acquired. When STOREn is zero, this menu is disabled.

The trigger condition (ENBLn, TRIGn, DSBn, TRIG PASS) specifies the reference point (trigger point) of data fetch. The patterns of ENGLn, TRIGn, DSBLn are ANDed by GROUP pattern and are used for actual patterns. As a RADIX of each GROUP, SYMBOL and CODE in addition to the value (BIN, OCT, HEX) can be used (if possible). So, an asterisk must be entered to USE on the SYMDEF menu screen.

## 3.4 Setting the Trace Condition (TRACE function)

• TRIGN		Specifies data pattern that is regarded as a trigger. All patters that correspond to this pattern are not a trigger. If data satisfies the limit specified by set value for the menu item below, it can be trigger. the NOT trigger can be specified by menu item [ ] on the left of TRIGn. The OR trigger can be specified by menu item [ORO]. When two trigger patterns are set, the earlier-coming pattern is considered as a
		trigger (OR1). OR2 is an OR trigger for three trigger patterns. OR3 is an OR trigger for four trigger patterns. Up to four trigger patterns can be set in the whole state analysis part.
● ENBLn	:	It is the previous pattern taht can detect the TRIGn pattern. After data corresponding to the ENBLn pattern appears, only data corresponding to the TRIGn pattern can be the trigger condition.
●DSBLn	:	- I Deliver that dischlar the MDICE mattern
•TRIG EVENT	:	(event). 1 to 256 (decimal) can be set.  The menu of trigger pulse on/off is as follows.
•TRIG OUT (SYNC)	:	Specify whether the specific pulse is output when data corresponding to the TRIGn pattern appears to the same BNC connector on the rear panel (not trigger). It is the TTL level and is the 500-ns

negative pulse.

#### 3.4 Setting the Trace Condition (TRACE function)

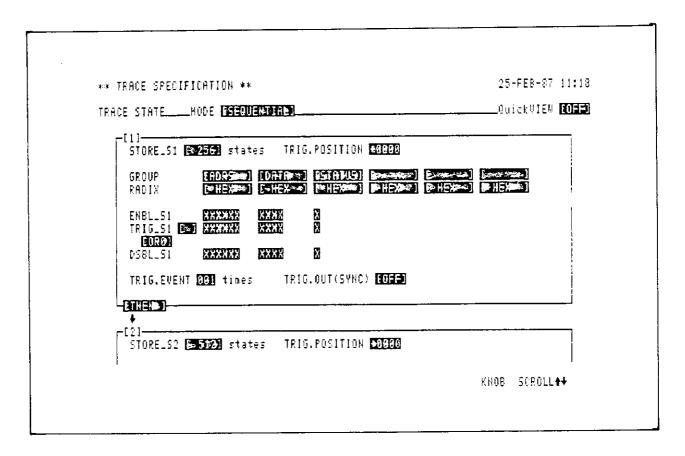


Figure 3 - 6 Trace Window Conduction

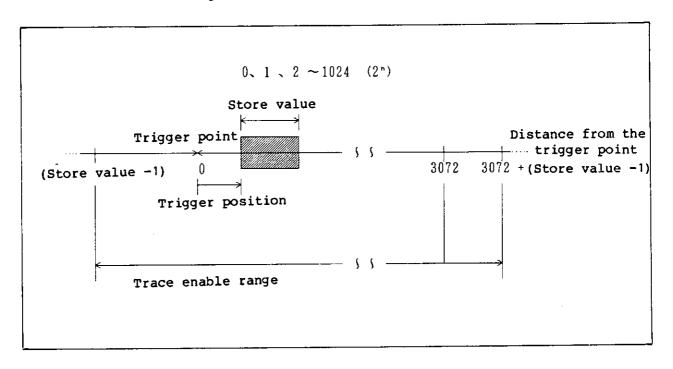


Figure 3 - 7 Store Condition

#### 3.4 Setting the Trace Condition (TRACE function)

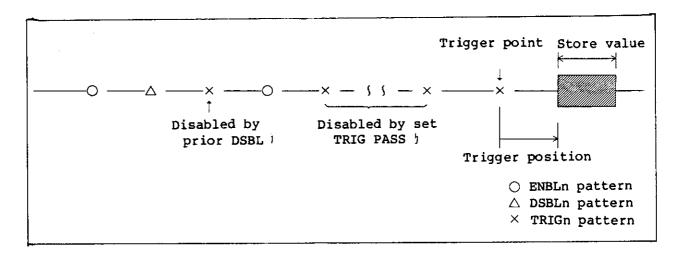


Figure 3 - 8 Trigger Condition

#### (2) Trace Window Conjunction

Trace window conjunction combines several trace window conditions and can make up the flexible trace condition for complicated data flow. The following four trace window conjunctions can be used (see Figure 3-9).

- STOP : Ends the test. It can be used even if the sum of STOREn is less than 1024 states.
- THEN: Starts the test under the next trace condition after the test is ended under a certain trace window condition. Up to four trace window conditions can be combined.
- AGAIN: Repeats the test under the previous trace window condition until acquisition memory is full.
- TOP : Returns to trace window condition 1 and continues the test.

The above trace window conjunctions can be used together.

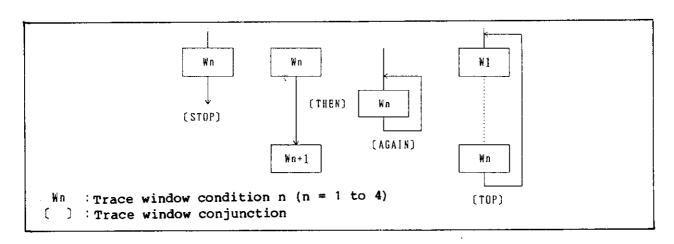


Figure 3 - 9 Function of Trace Window Conjunction

#### 3.4 Setting the Trace Condition (TRACE function)

#### (3) Trace Window Condition and Trace Window Conjunction

The following explains some combinations of the trace window condition and trace condition conjunction (see Figure 3-10 (a) to (f)).

- Figure 3-10 (a): Shows the currently-set logic analyzer and the initial menu screen. As a store value, other than 1024 can also be obtained.
- Figure 3-10 (b): Trace window condition 1 is repeated by AGAIN.
   Figure 3-10 (c): Trace window conditions 1 to 4 are connected by THEN.
- Figure 3-10 (d): After data is obtained by previous trigger in advance, the succeeding trace window condition is repeated.
- Figure 3-10 (e): After trace window conditions are set, trace window condition 1 is set again.
- Figure 3-10 (f): Shows the configuration of sequential trigger to be realized.

  ENBLn and TRIGn (n = 1 to 3) are used for the

ENBLn and TRIGn (n = 1 to 3) are used for the enable pattern. They are eight-level sequential trigger. Since the trance window condition still

has the DSBLn pattern, it can be set more complicatedly.

(a) <Set> --- 1024 <del>----></del> W1(1024) (STOP) ₩1 🖾 3 - 10 (a) (b) <Set > **├**─512 → W1 (512) (AGAIN ) **⊠** 3 - 10 (b) (c) <Set> 256 256 256 256 W1(256) (THEN) W2 (256) (THEN) W4 W3 (256) ₩1 W2 ₩3 (THEN) **#4(256)** (STOP)

Figure 3 - 10 Combinations of Window Condition and Trace Window Conjunction

## 3.4 Setting the Trace Condition (TRACE function)

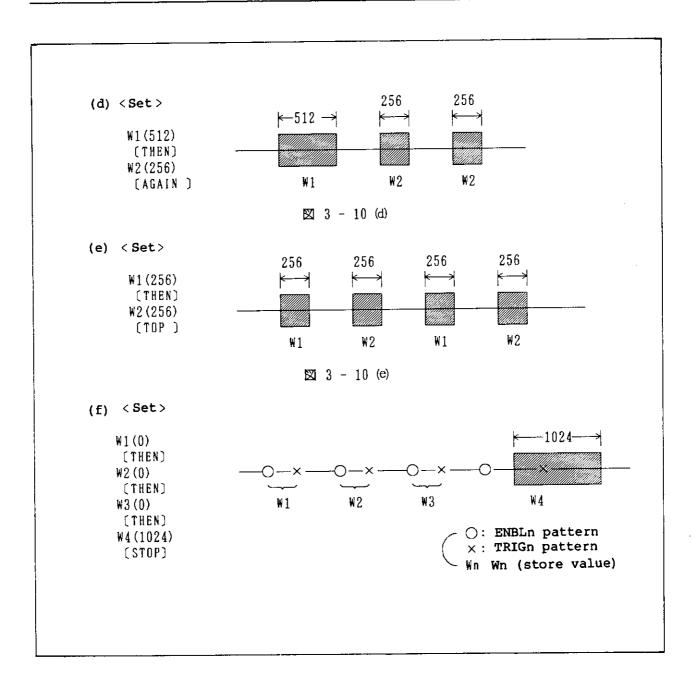


Figure 3 - 10 Combinations of Window Condition and Trace Window Conjunction (cont'd)

3.5 Displaying Acquisition Data in State
Analysis Part (DISPLAY function)

- 3.5 Displaying Acquisition Data in State Analysis Part (DISPLAY function)

  DISPLAY displays data fetched in acquisition memory in several formats to analyze.
  - 3.5.1 Menu Item and Display Format

Figures 3-11 and 3-12 show examples of acquisition data to be displayed.

Figure 3-11 shows the example of acquisition data to be displayed in the TRACE TRIG mode.

Figure 3-12 shows the example of acquisition data to be displayed in the SEQUENTIAL mode.

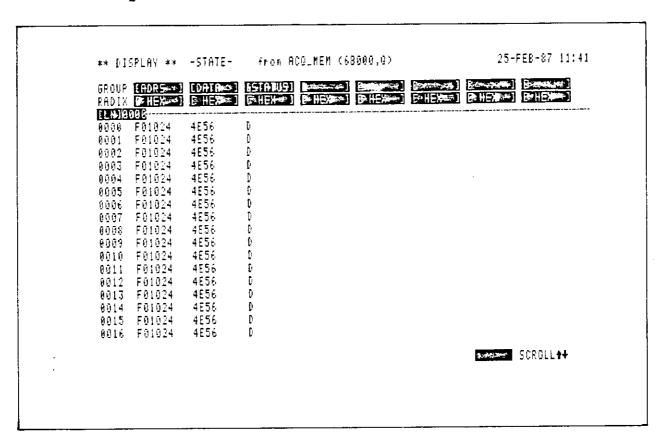


Figure 3 - 11 Example of Test Data to be Displayed

3.5 Displaying Acquisition Data in State
Analysis Part (DISPLAY function)

** DI	SPLAY **	-STATE-	trem At	COLMEM (6	3000.0)		25-	FE8-87 11:3
	[ADRS==]	[DATA = ]	[STABU9]	<b>[10</b> 75 2 4 4 ]	Biograph			
RADIX	E-HEX-	[ HEXTER]	[B. Elevan]	HE PARTY	⊕HEX⊶3	- di Britis	PHEØ=1	المستندنة ادائت
(EN)2 0000	F01060	8004	D					
<u> </u>		3200	<u> </u>					
0902	F01064	2800	Ď					
0001 0003	F01056	B883	Ď					
0994	F01058	620E	Ď					
9995	F0106A	2F04	D.					
0006	F0:060	2F01	D					
9997	000FD6	090A	A					
6998	800FD4	0000	A					
0009	F0106E	2F0B	D					
0010	000FD2	0019	R					
0011	000F00	0000	R					
0912	F81978	6182	0					
0913	999FCE	0400 0400	A A					
9914 9915	000FCC 000FC8	0090 00F0	n B					
0016 0016	000FC8	1972	A					
0010	ของกรก	1012	11					
							sinker residen	SCROLL*+

Figure 3 - 12 Example of Test Data to be Displayed: SEQUENTIAL Mode

The underline displayed by halftone in the SEQUENTIAL mode indicates the trigger mark. When acquisition memory is divided using several trace window conditions, the memory division boundary mark and trigger mark are not displayed as shown in Figure 3-13. When the memory division boundary mark overlaps the trigger mark, the trigger mark is displayed normally (when only the trigger overlaps, halftone is displayed). The following explains set menu items and the result.

#### GROUP

: GROUP has up to eight menu items. When the SELECT key is pressed to select GROUP defined on the CONFIG menu screen, the arbitrary order can be displayed. Data in the same GROUP can be overlapped for display in different places. When the blank is specified, no data for the specified GROUP can be displayed. The width of GROUP to be displayed is changed greatly by defined channel number and RADIX. When a combination of GROUP and RADIX exceeds the width displayed on the CRT, it is not allowable.

3.5 Displaying Acquisition Data in State
Analysis Part (DISPLAY function)

- RADIX : A radix to display data for specified GROUP is set in this menu item. One of BIN (binary), OCT (octal), DEC (decimal), HEX (hexadecimal), ASCII (7- or 8-ch GROUP only), MNEM (data for PK only), SYMBOL (see Item 3.6.3), and CODE (only the group less than 8-ch; see Item 3.6.4) can be set.
- Line No. : When a decimal number is entered to this menu item by ENTRY key, data for line No. of the number is displayed. For a default, an input prompt appears in the hundreds digit. It can be moved to the other digit by ← and → .

Data scroll is explained below. Displayed data can be scrolled up and down at optional speed by scroll knob (turning the knob clockwise allows the data to move up). When the PAGE i and keys are pressed, the page scrolls up and down every displayed 10 lines.

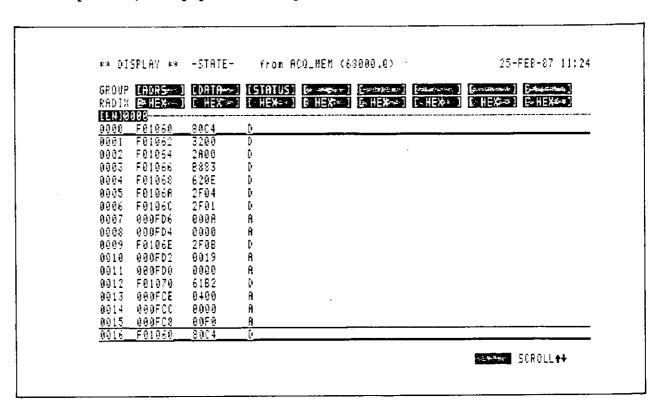


Figure 3 - 13 Example of Test Data to be Displayed when Memory is Divided (STORE = 16, AGAIN)

#### R47252A

#### PERSONALITY KIT INSTRUCTION MANUAL

# 3.5 Displaying Acquisition Data in State

Analysis Part (DISPLAY function)

To analyze the state smoothly using DISPLAY function, some display states are enabled.

Figure 3-14 shows the example of test data to be displayed.

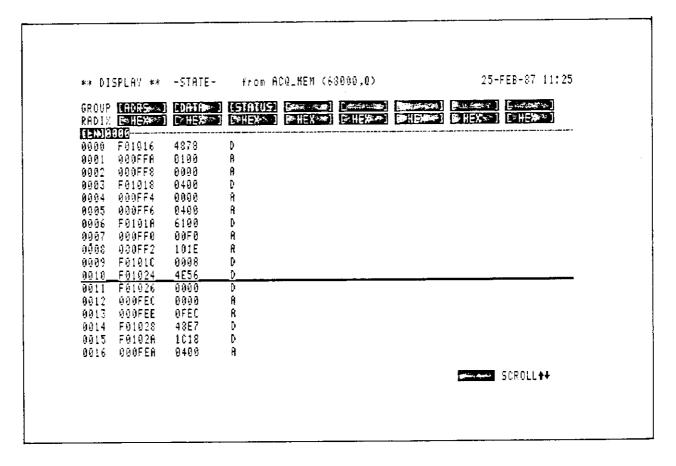


Figure 3 - 14 Example of Test Data to be Displayed

#### (1) Display in the QUEUE Sample Mode

Figure 3-15 shows the example of data fetched in the QUEUE sample mode by mnemonic.

3.5 Displaying Acquisition Data in State
Analysis Part (DISPLAY function)

** DISPLAY ** -STATE- from ACQ_MEM (68000,0)	25-FEB-87 11:2
GROUP [ADRS ] [DATA ] RADIX EMERGO ] [MINER ] with[S-by-S]	ESTATUS) [C] P. CODES] [C HEX=-]
14N)2000	SIPRGIRD
000: 000FFA - 0100/super_data_wr	SLDATLWR
0002 000FF8 0000/super_datalwr	SLDATLWR
0903 F01018	S_PRO_RD
0004 000FF4 0000/super_data_er	SLDATLWR SlDATLWR
0005 000FF6 0400/super_data_vr	S_PRG_RD
0006 F0101A BSR.L F01024 0007 000FF0 90F0/super_data_wr	S_DAT_WR
0007 000FF0	S_DAT_WR
0000 000FF2 191E/Superlusvaler	S_PRG_RD
0010 F01024 LINK 86.#0000	SIPRGIRÔ
9911 F01926	SIPRGIRD
0012 000FEC 8000/super_data_wr	S_DAT_WR
0013 000FEE BFEC/super_data_wr	S_DAT_WR
0014 F01028 MOVEM.L A34/D345,-(A7)	SIPROIRD
0015 F0102A	SLPRGLRD
0016 000FEA 0400/super_data_wr	S_DAT_WR
	SOROLL##

Figure 3 - 15 Example of S-by-S to be Displayed in QUEUE Sample Mode

Since the 68000/68010 prefetches the instruction, the bus is not used in sequence to fetch and execute the instruction. One instruction is fetched, the other instruction is sometimes not be executed. In the QUEUE sampling mode, data is sampled by synchronizing the internal queue of 68000/68010, the instruction is fetched and executed. Such sequential display is done, so it is useful for debugging. Part "...." in [DATA] displayed by mnemonic is a part of instruction code. It indicates that the previous mnemonic (or operand) contains the data. A period is hexadecimal one-digit data.

As shown above, the method of displaying data fetched by R47252A is called S-by-S (State-by-State) display mode. The other mode eliminates "...." that is unnecessary to analyze data and enables highly-dense display. This mode is called PACKED display mode. Figure 3-16 shows the PACKED display mode with the same data as in Figure 3-15.

3.5 Displaying Acquisition Data in State Analysis Part (DISPLAY function)

** DISPLAY **	-STATE- from ACQ_NEM (68000,0)	25-FE8-87 11:2
	GDATA™ E NYEMPJwithEPASHEDJ	ESTABLES BY HEND
ELN10000 0000 F01016	PEA 030400.W	S_PRG_RD
0001 000FFA	0100/superidatai⊎r	SUDATLWR
0002 000FF8	0000/super_data_wr	S_DAT_WR
0004 000FF4	ปียีซีซี/super_data_wr	SLDATLWR
0005 000FF6	0400/super_data_er	SLDATLWR
0006 F0101A	BSR.L F01024	SIPRGIRD
0007 000FF0	00F0/super_data_wr	S_DAT_UR
0008 000FF2	101E/super_data_wr	S_DAT_WR
0010 F81024	LINK A6,#0000	<u> </u>
0012 000FEC 0013 000FEE	0900/superidatalwr 0FEC/superidatalwr	S_DAT_WR
9014 F01928	MOUEN.L A34/D345(A7)	S_PRG_RD
0014 F01920 0016 000FEA	0400/super_data_er	SIDATINA
0017 000FE8	0000/super_data_wr	SIDATIWR
0018 000FE6	0402/super_data_wr	SIDATLWR
0019 909FE4	0000/super_data_wr	SLDATLWR
0020 000FE2	0036/super_data_wr	S_DAT_WR
		SCROLL <b>↑</b> ↓

Figure 3 - 16 Example of PACKED to be Displayed in QUEUE Sample Mode

#### R47252A PERSONALITY KIT

# INSTRUCTION MANUAL

3.5 Displaying Acquisition Data in State
Analysis Part (DISPLAY function)

## (2) Displaying BUS Sample Mode

Figure 3-17 shows the example of data fetched in the BUS sample mode by mnemonic. Such data has been tested under the same trace condition as in Figures 3-14 and 3-15 (only setting CONFIG is different). In the BUS sample mode, the 68000/68010 microprocessor fetches data to access the bus. The previous instruction prefetches the next instruction in the 68000/68010 microprocessor, so the instruction code on the bus and the operation of operated bus after execution of the code are not continuous.

The part "." in data displayed by mnemonic is a part of an instruction code and indicates that it is included in the previous mnemonic (and operand). "." indicates the hexadecimal one digit.

** DISPLAY **	-STATE- From ACQ_MEM (68000,B)	25-FE8-87 11:
GROUP EADRS	1 EDATA XXI 1 EXAMENTI	
8000 000FAE	000A/super_data_wr	5_DAT_WR
0901 000FAC	0000/superidatalwr	SLDATLUR
0002 F01070	6182/opucode	SIPRGIRD
0003 000FAA	0002/super_data_wr	S_DAT_WR
0004 000FA8	0000/superidatal⊌r	S_DAT_WR
0905 F01972	4FEF/op_code	SIPRGIRD
0006 000FA6	0400/super_data_wr	S_DAT_WR
0007 000F84	0900/super_data_er	S_DAT_WR
0008 000FA0	00F0/super_data_wr	SIDATINR
0009 000FA2	1972/super_data_wr	S_DAT_WR
0010F01024_	LINK A6,#0000	S_PRGURD
0011 F01026		SIPRGIRD
0012 F01028	MOVEN.L A34/D345,-(A7)	SIPRGIRD
0013 000F9C	0000/super_data_wr	S_DAT_WR
0014 000F9E	0FC4/super_data_wr	S_DAT_WR
0915 F0102A	****	SIPRGLRD
0016 F0102C	MOVEA.L 0008(A6),A4	SIPRGIRD
		SCROLL++

Figure 3 - 17 Example of Data to be Displayed in BUS Sample Mode

3.5 Displaying Acquisition Data in State
Analysis Part (DISPLAY function)

## 3.5.2 68000/68010 Reverse Assembly Format

- (1) For mnemonic of operation code, the Motorola's 68000/68010 standard assembler format is used (reference: M68000 Microprocessor User's Manual REV 4.00, 1984).
- (2) All values that appear in the operand are represented by hexadecimal, so the symbol indicating the base of values is not used.
- (3) To the operation code that can treat the different operand in size, one of B (byte), W (word), or L (long word) is added. If the operation code is the same as above, the symbol specifying the size is not added to the code requiring CCR, SR, or USP as a operand.
- (4) S (short) and L (long) is added to Bcc, BRA, and BSR of branch instructions according to the displacement size.
- (5) # is added to immediate data. If the size of data is three or four bits, it is displayed by one digit of hexadecimal. If it is eight bits, it is displayed by two digits of hexadecimal. If it is 16 bits, it is displayed by four digits of hexadecimal. If it is 32 bits, it is displayed by eight digits of fixed length.
- (6) If the displacement other than the branch instruction is eight bits, it is two digits of hexadecimal. If it is 16 bits, it is displayed by four digits of fixed length.
- (7) The operand (8- or 16-bit displacement) of branch instruction (Bcc, BRA, BSR, and DBcc) is converted into the 24-bit absolute address regardless of the size, and is displayed by six digits of hexadecimal.
- (8) When the jump instruction (JMP, JSR) and memory operand are specified by absolute address, the absolute address (16 or 32 bits) used for an execution address is changed to 24-bit absolute address. To indicate the size of each address, "\_W" (word) and "\_L" (long word) are added.

#### Example:

JMP hhhhhh\_W (h is one digit of hexadecimal)
JSR hhhhhh\_L

- (9) When the GROUP (ADRS) is displayed by SYMBOL, the operand address is displayed by SYMBOL if possible. The display format is as follows. SYMBOL name + hhhhhh (h is one digit of hexadecimal) SYMBOL name - hhhhhh
- (10) The register list is displayed by MOVE instruction as follows.

  The address register (starting with A) and data register (starting with D) are displayed in order. They are separated by "/". When more than register Nos. are continuous, the first and last Nos. are displayed. They are separated by "-".

3.5 Displaying Acquisition Data in State Analysis Part (DISPLAY function)

- (11) The name of stack pointer (SP, USP, SSP) is used only when the instruction is specified explicitly.
- (12) The ILLEGAL instruction ( $4AFC_H$ ) is used for a formal operation code. It an undefined instruction and unmounted instruction are found, hhhh/illegal is displayed.

3.6 Defining SYMBOL and CODE (SYMDEF function)

# 3.6 Defining SYMBOL and CODE (SYMDEF function)

The R47252A (state analysis part) can use the user-defined SYMBOL name and CODE name in addition to values or fixed code to set the trace condition (TRACE function) or display and analyze test data (DISPLAY function). SYMBOL can be applied to the arbitrary channel number to the GROUP, giving one SYMBOL name to the string of certain values (or one value). The rate of debugging can be improved by using the label name, variable name, and step name to development a program. CODE can be applied to the GROUP which is less than 8-channel, giving one CODE name to one value. The code table can be created easily.

## 3.6.1 SYMDEF Menu Screen

Press the \_\_\_\_\_, and the menu screen of SYMDEF is displayed (see Figure 3-18). The menu screen of SYMDEF depends on the number of defined GROUPs, and consists of up to 12 partial menu screens which are shown in Figure 3-19. Set data displayed once on the CRT defines 16 SYMBOLs (or CODEs) or less which are on the one partial screen of them. Data defining one SYMBOL or CODE is represented by one line of related several menu items. This line is called a menu item line. The line number for menu item line is variable. For easy-to-see display, only one line is displayed inversely. When the menu screen contains 17 lines or more, the whole partial menu screen can be displayed by scroll knob or PAGE  $\widehat{\ \ }$  and  $\widehat{\ \ }$  . Using the scroll allows you to access to a proper part on the partial menu screen at proper speed. Using the PAGE 🗻 and 🗓 allows you to feed the page every 10 lines of menu item line. The scroll mark [ ] or  $\downarrow$  } at the bottom of the CRT screen can judge that part of partial menu screen is not displayed on the CRT. When displaying the partial menu screen that is different from the currently-displayed screen, change the menu item of GROUP (select from defined GROUP name) and TYPE (select from SYMBOL and CODE). Fixed R47252A has no partial menu screen corresponding to the GROUP name, DATA (for SYMBOL and CODE).

# 3.6 Defining SYMBOL and CODE (SYMDEF function)

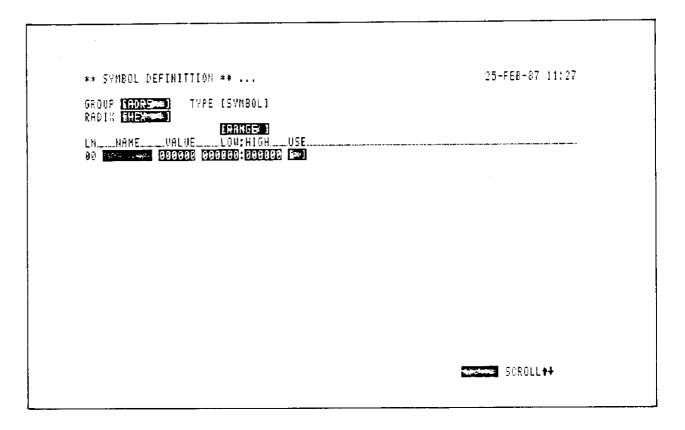


Figure 3 - 18 Initial Menu Screen of SYMDEF

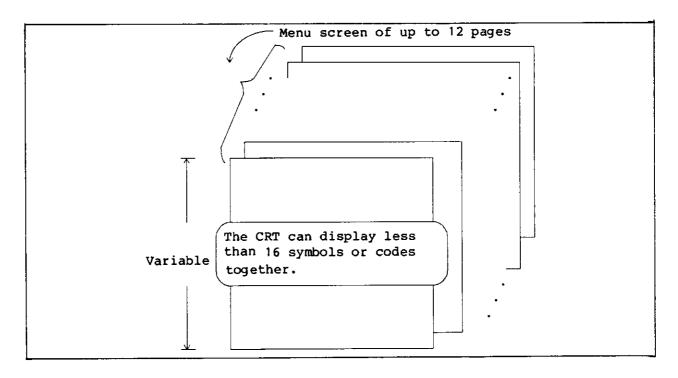


Figure 3 - 19 SYMDEF Menu Screen

# 3.6 Defining SYMBOL and CODE (SYMDEF function)

#### 3.6.2 CODE Cable for 68000/68010

The R47252A already defines the CODE table to the GROUP (STATUS) (see Figure 3-20).

Abbreviations used in this section are as follows.

U : User state

S : Supervisor state

DAT : Data area PRG : Program area

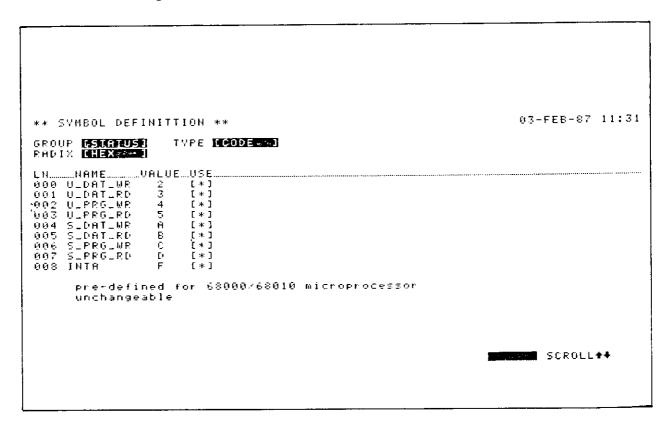


Figure 3 - 20 Defined CODE Table (status of 68000/68010)

# 3.6 Defining SYMBOL and CODE (SYMDEF function)

#### 3.6.3 Defining SYMBOL

On the initial menu screen of SYMDEF, the partial menu screen of SYMBOL is displayed by first-defined GROUP name (Figure 3-18). On the menu items of GROUP, select the GROUP name to define SYMBOL. Issue an input prompt to the menu item line, and input the data to menu lines as follows.

• NAME: Enter eight alphanumeric characters or less as the SYMBOL name. The previous space is enabled (the effect of scroll down can be obtained).

VALUE: Enter the reference value of SYMBOL.

 LOW: Enter the minimum of numeric string. If the just above menu item is RANGE, enter the absolute value. If it is OFFSET, enter the relative value from VALUE.

• HIGH : Enter the maximum of numeric string. If the just above menu item is RANGE, enter the absolute value. If it is OFFSET, enter the relative value from VALUE.

• USE : The SELECT key is pressed to use SYMBOL on the menu screen of TRACE, so the number of usable SYMBOLs is limited. When an asterisk is specified in this menu items, the SYMBOL can be used on the TRACE screen. Regardless of this specification, all SYMBOLs can be used on the menu screen of DISPLAY.

Figure 3-21 shows the example of SYMBOL to be applied. If SYMBOL is applied to the N-channel GROUP, the value of GROUP is 0 to  $2^{N-1}$ . When VALUE, HIGH, and LOW are set, the range of SYMBOL that can be referred in their values. Except that LOW < HIGH and the duplication of value is not allowed, there is no limit among VALUE, HIGH, and LOW. Figure 3-21 (a) : It is considered to be the most general setting

of VALUE = LOW. The procedure name, function name, and sub-routine name are used for a SYMBOL name. These names are specified by VALUE, HIGH, and LOW. On the menu screens of TRACE and DISPLAY, the value can be referred in the form of SYMBOL name + n (offset).

Figure 3-21 (b) : It can be applied to the stack if VALUE = HIGH.

On the menu screen of TRACE and DISPLAY, the value can be referred in the form of SYMBOL name - n (offset).

Figure 3-21 (c): It can be applied to the stack frame if VALUE ranges from LOW to HIGH. On the menu screen of TRACE and DISPLAY, the value can be referred in the form of SYMBOL name + n or SYMBOL - n.

Figure 3-21 (d) : It is a transformation of Figure 3-20 (a) if VALUE does not range from LOW to HIGH.

Otherwise, SYMBOL is enabled if VALUE = LOW = HIGH. In this case, only the value of VALUE is set.

# 3.6 Defining SYMBOL and CODE (SYMDEF function)

When adding or deleting the menu item line, use the ①, on and of the line of the line item line newly, use the ①. Set the input prompt to the bottom line and press the ①. A new menu item line is added directly after the menu item line on which the input prompt is, then the prompt moves to the new menu item line.

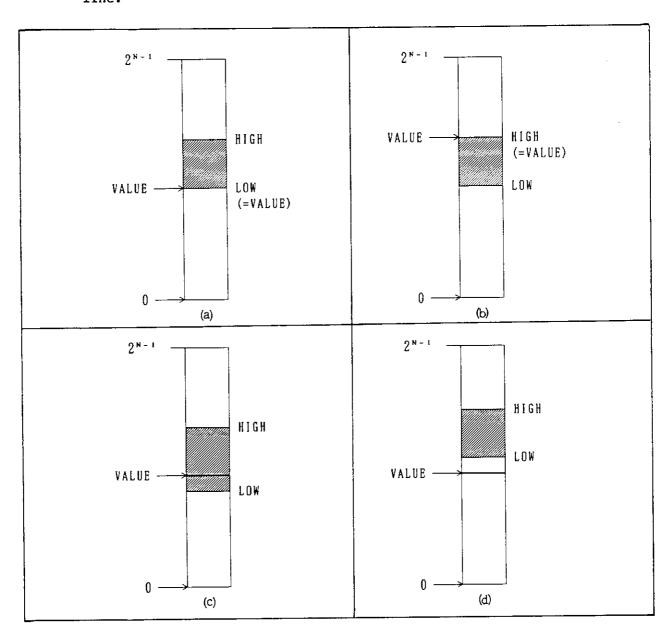


Figure 3 - 21 Example of SYMBOL to be Applied

INSERT

# 3.6 Defining SYMBOL and CODE (SYMDEF function)

Press the [], and a new item line is added directly before the menu item line on which the input prompt is. Press the [] , and the menu item line with an input prompt is deleted. If the menu item line consists of one line and it has an input prompt, its content is cleared. Duplication between different SYMBOL values (VALUE, LOW to HIGH) is not allowable. The number of values that the SYMBOL can define is up to 100 per GROUP. The maximum every GROUPs is up to 200. Up to 50 of the value can be used per GROUP on the menu screen of TRACE. Figures 4-14 (a) and (b) shows the examples of SYMBOL to be applied. The same definition is shown by RANGE in Figure 3-22 (b) and is shown by OFFSET in Figure 3-22 (b).

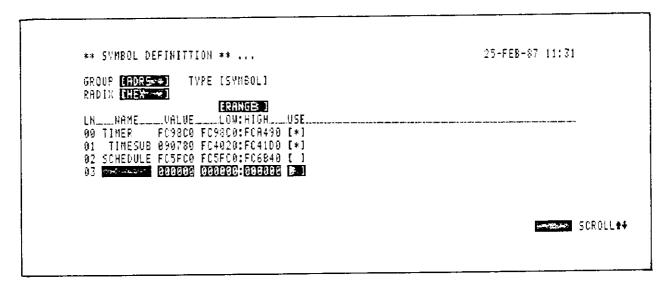


Figure 3 - 22 (a) Example of SYMBOL to be Applied (displayed by RANGE)

```
25-FEB-87 11:31
** SYMBOL DEFINITTION ** ...
GROUP EADRS
                  TYPE ISYMBOLI
RADIX HEX
                          [OFFSET]
    __NAME___.
             __VALUE_
                         _LOB:HIGH..
00 TIMER FC9860 +000000 +000800 [*]
01 TIMESUB 090780 +F338A0:+F33A50 [*]
02 SCHEOULE FC5FC0 +000000:+000880 [ ]
             000000 +0000000:+000000 [ ]
                                                                                    SCROLL#↓
```

Figure 3 - 22 (b) Example of SYMBOL to be Applied (displayed by OFFSET)

# 3.6 Defining SYMBOL and CODE (SYMDEF function)

## 3.6.4 Defining CODE

CODE can be defined to the eight-channel GROUP or less in the same way as in SYMBOL. CODE is to define one CODE name to one value, and is like the ASCII code as an image (the ASCII code can be used on the menu screen of DISPLAY). SYMBOL and CODE can be defined to the same GROUP (they are treated as different partial menu screen in this case). To define the CODE, select the GROUP name and determine TYPE as a CODE. Enter the following data to menu items on the menu item line.

 NAME: Enter eight alphanumeric characters or less as a CODE name. The previous space is enabled (the effect of scroll down is enabled in DISPLAY).

VALUE: Enter the value of CODE.

 USE: Determine whether it is used on the menu screen of TRACE (when an asterisk is specified, it can be used).

The CODE is used to define the code table, but it need not define all values. The number of values that the CODE can define is up to 256 per GROUP (28 for eight-channel GROUP). The total of values is 512 every GROUPs. Up to 50 values per GROUP of them can be used on the menu screen of TRACE. Figure 3-23 shows the example of CODE to be defined. For R47252A, defined CODE is enabled to GROUP "STATUS".

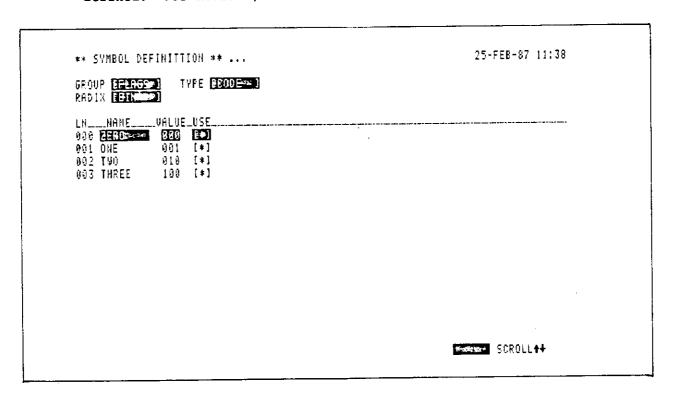
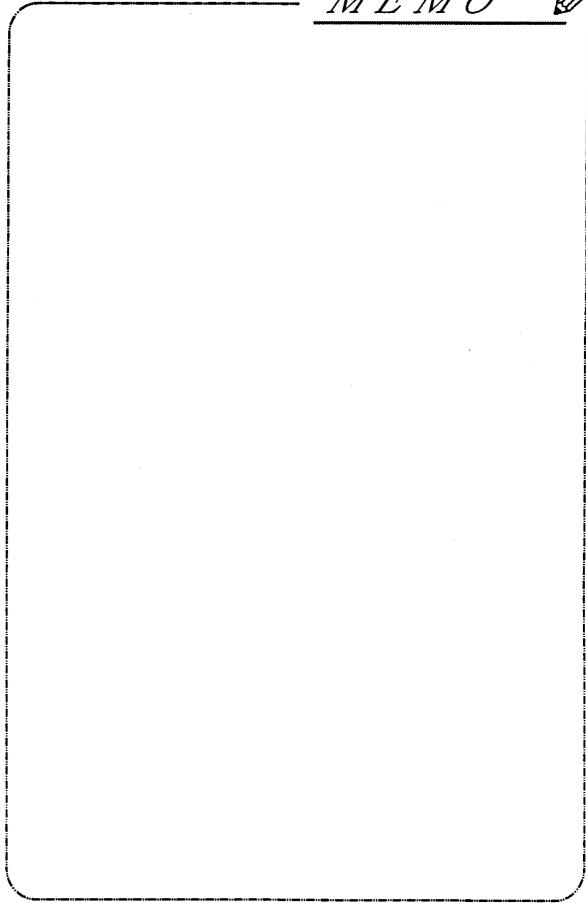


Figure 3 - 23 Example of CODE to be Defined

# MEMO



4.1 Outline

- 4. HOW TO OPERATE AS S & T COMBINATION ANALYZER
- 4.1 Outline

This chapter explains how to operate the R47252A as a combination analyzer by combination of state and timing functions.

#### 4.2 Test

When the S & T COMBINATION mode is selected on the COMBINATION OF MODULE screen in Figure 3-1, the state analysis part and timing analysis part can be operated simultaneously. When both analysis parts arms the trigger, the timing analysis part can be corresponded to the state analysis part. Figures 4-1 and 4-2 shows the trace screen and status to be executed in the  $(T \rightarrow S)$  and  $(S \rightarrow T)$  modes.

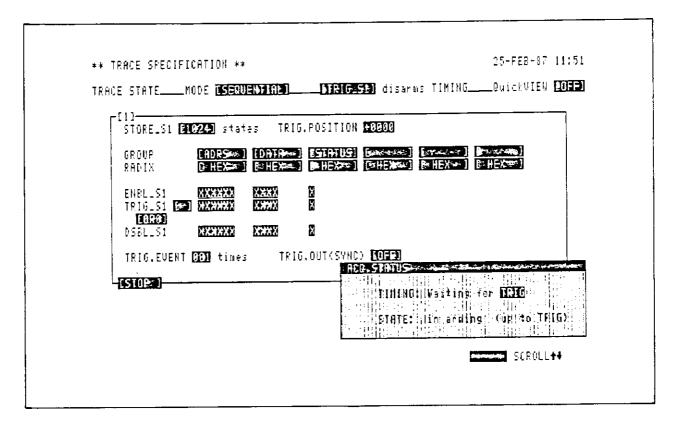


Figure 4 - 1 Screen and Status to be Executed in TRACE S & T  $(T \rightarrow S)$  Mode

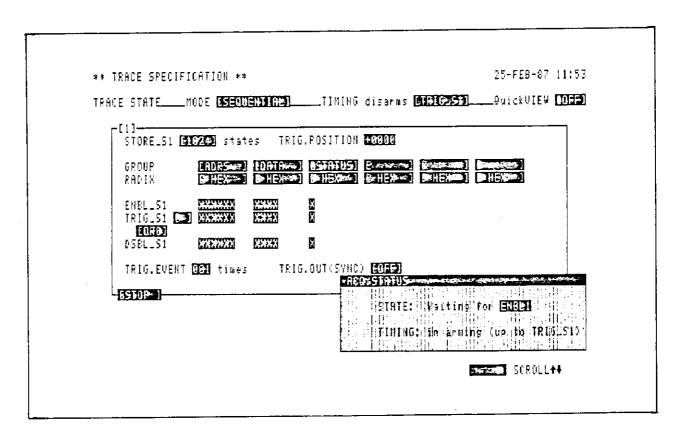


Figure 4 - 2 Screen and Status to be Executed in TRACE S & T (S $\rightarrow$ T) Mode

#### (1) Status of State Analysis Part

The following messages are displayed after "STATE". The underline is displayed by normal blink.

- in arming (up to TRIG T)
  - This message indicates that the state analysis part (or the specific trace window condition) is arming.

    Under the arming state, ENBLn, TRIGn, and DSBLn are not detected. Arming is released by TRIG\_T in the timing analysis part.
- waiting for ENBLn
  - : This message is displayed while the state analysis part waits for data with ENBLn pattern. Under the arming state, ENBLn, TRIGn, and DSBLn are detected. The message is also displayed when the clock does not come from the microprocessor of SUT.
- waiting for TRIGn
  - : This message is displayed when the state analysis part waits for data with TRIGn pattern.
- in delaying (STOREn)
  - : This message is displayed when the trigger is detected and fetched data does not satisfy the number set to STOREn.

4.2 Test

• acquisition ended

This message is displayed when the state analysis part ends the test.

# (2) Status of Timing Analysis Part

The following messages are displayed after "TIMING". The underline is displayed by normal blink.

• in arming (up to TRIGn)

: This message indicates that the timing analysis part is arming. Under the arming state, ENBL\_T and TRIG\_T are not detected.

Arming is released by TRIGn in the state analysis part.

• waiting for ENBL T

- : This message is displayed when the timing analysis part waits for data with ENBL\_T pattern.
- waiting for TRIG T
  - : This message is displayed when the timing analysis part waits for data with TRIG\_T pattern.
- in delaying
  - This message is displayed when the trigger is detected and fetched data does not satisfies the size of acquisition memory (only when the low-speed clock is detected).
- acquisition ended
  - : This message is displayed when the timing analysis part ends the test.

After all tests are ended, the DISPLAY menu screen of the state analysis part is automatically displayed in the TRACE STATE and TRACE S & T (S $\rightarrow$ T) modes. The DISPLAY menu screen of the timing analysis part is automatically displayed in the TRACE STATE and TRACE S & T (T $\rightarrow$ S) modes. When the key other than MENU key group and SIP is pressed during test, "ignored!" is displayed and entered key is ignored.

When the key in the MENU key group is pressed, the test is interrupted forcibly and "aborted!" is displayed. The screen is changed to specified menu screen.

When the [ST P] is pressed, the test is aborted similarly. Except message, "acquisition ended!" displayed in both cases, correct data is not displayed. The menu screen of state analysis part is changed to

that of timing analysis part by

4.3 Relation Between State Analysis Part and Timing Analysis Part

# 4.3 Relation Between State Analysis Part and Timing Analysis Part

#### (1) For S & T (S $\rightarrow$ T) Mode

The TRACE S & T (S $\rightarrow$ T) mode sets TRIGn in [TRIGn] disarms TRIG\_T (a default is TRIG1). "disarm" is to release the arming state. Under the arming state, no trigger is detected. Figure 4-3 shows the test process in the S & T (S $\rightarrow$ T) mode. In the figure, the detail of trigger condition (ENBL) is omitted. In Figure 4-3, the trigger condition is set together with the state analysis part and timing analysis part. The timing analysis part is in the arming state until previously-specified TRIGn (n = 1 to 4) is detected in the state analysis part. After the arming state is released, the trigger condition in the timing analysis part is enabled.

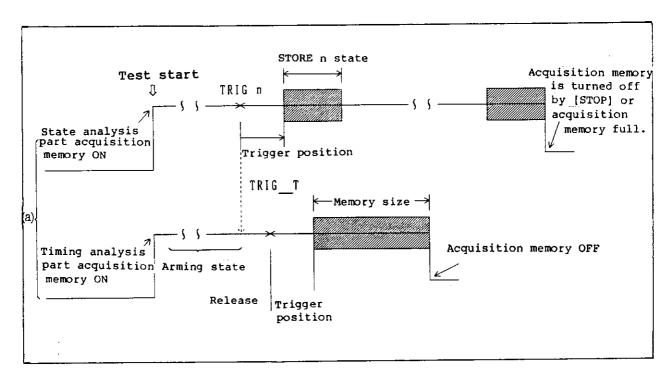


Figure 4 - 3 Test Process in TRACE S & T (S $\rightarrow$ T) Mode

#### (2) For S & T $(T \rightarrow S)$ Mode

The S & T  $(T \rightarrow S)$  mode sets TRIGn in TRIG\_T disarms [TRIG n] (a default is TRIG1). Figure 4-4 shows the test process in the S & T  $(T \rightarrow S)$  mode. In the figure, the detail of trigger condition is omitted. In Figure 4-4, the trigger condition is set together with the state analysis part and timing analysis part. The trace window condition n in the state analysis part is under the arming state until TRIG\_T is detected in the timing analysis part. The trace window condition earlier than trace window condition n is always executed.

4.3 Relation Between State Analysis Part and Timing Analysis Part

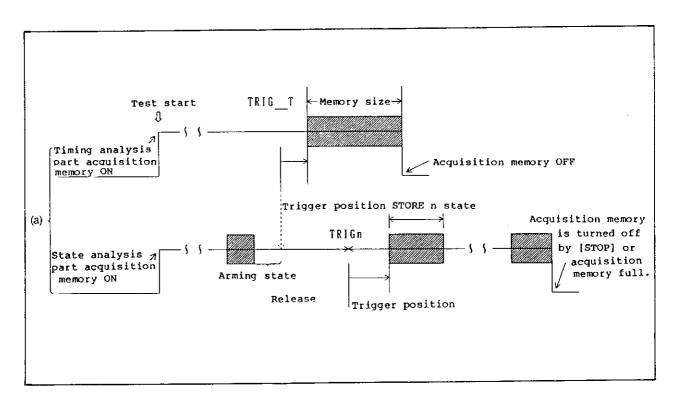


Figure 4 - 4 Test Process in TRACE S & T  $(T \rightarrow S)$  Mode

- NOTE -The R47252A judges whether data latched once by sampling clock is the trigger. After the trigger pattern is generated actually, note that the R47252A delays by up to one sampling clock to recognize it as a trigger. In the TRACE S & T  $(T \rightarrow S)$  mode, operate the timing analysis part at slower sampling clock than the speed of the µP to be tested by state analysis part. When data fetched by (for example, 1-ms) state analysis part is tested, the operation of the  $\mu P$  cannot be tested correctly if the actual TRIG T generation point does not correspond to the arming release point to the state analysis part. Be sure to set the sampling clock to the clock rate of the state analysis part or equivalent. The sampling clock of the state analysis part is always equivalent to the instruction cycle of the  $\mu P_{\bullet}$ TRIG T Timing analysis part Timing analysis part sampling clock lms≪ Arming release State analysis part Even if there is TRIG n, it is not detected.

5.1 Testing the Microprocessor Probe

5.	OPERATION	CHECK
----	-----------	-------

5.1 Testing the Microprocessor Probe

The R47252A uses the multiple-pin connector or cable for test, so a trouble such as contact error sometimes occurs. To avoid such error, the signal system can be checked easily.

- ① Install attached probe test adapter on the probe test connector on the rear panel of the TR4726.
- ② Connect the microprocessor probe to the probe test adapter to use the DIP plug cable or through the DIP IC package to use the DIP clip cable (see Figure 5-1).
- ③ Display the menu screen of CONFIG, set [COMBINATION]. Move the cursor by knob, and select STATE ANALYSIS ONLY. Press the SELECT key, change the screen to [SET UP] screen, and press the
- 4 Change the screen to the menu screen of TRACE, and press the
- 5 Press the NN , and start to check.
- 6 If the screen is the same as Figure 5-2, the normal operation of the R47252A can be checked.

# 5.1 Testing the Microprocessor Probe

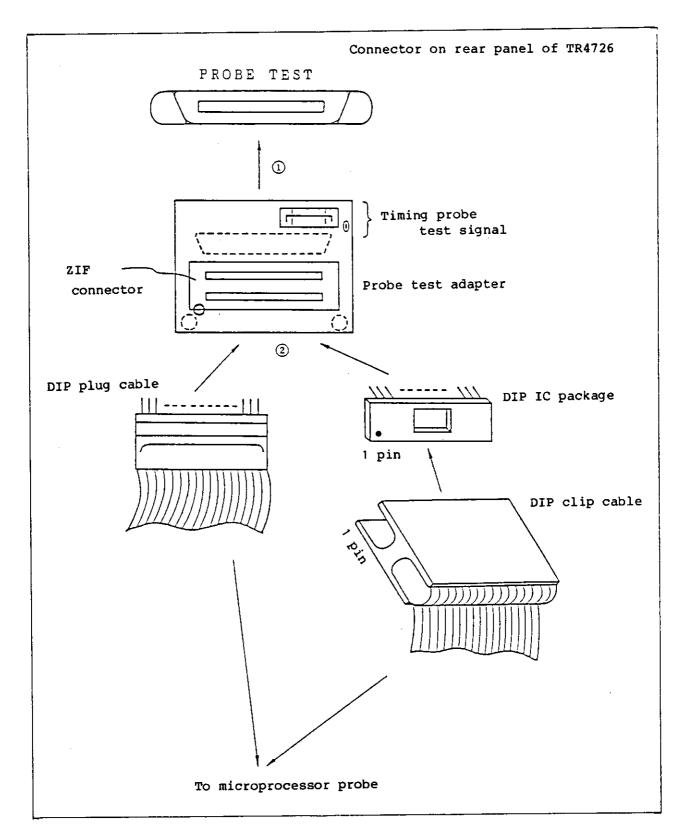


Figure 5 - 1 Connection for Probe Test

5.1 Testing the Microprocessor Probe

	SPLAV **								
		[DATA::4]				S I CURA	Berman (PaHEX-Ma)	Fatter:	
	逐 HEXix ]	B HEX™]	Be HE片中]	E: HEX **>]	[- HEX-=]	R HEXE	5-11-11-11	الكفياتاتين	
EF M33									
9999	<u>ଜ୍ଞତ୍ତ୍ତ୍ତ୍</u>	<u> </u>	<u> </u>				*		•
9001	111110	1111	2						
9892	222222	3222	4						
9003	333332	3333	6						
តូមូអូ4	444444	4444	8						
0005	555554	5555	A						
9996	666666	6666	C						
0007	777776	7777	E						
0008	888888	8888	1						
9009	999998	9999	3						
0010	688666	8888	5						
0011	88888A	6888	7						
0012	000000	0000	9						
9013	000000	0000	В						
8614	EEEEEE	EEEE	D						
0015	999999	0000	B						
0016	111110	1111	2						
****									
							<b>阿里斯斯斯</b>	SCROLL∱₹	

Figure 5 - 2 Result of Microprocessor Probe Test

# MEMO

6.1 Storing the R47252A

- 6. NOTES ON STORAGE AND TRANSPORTATION OF R47252A
- 6.1 Storing the R47252A

The range of temperatures under which the R47252A is stored is -10  $^{\circ}$  to +60  $^{\circ}$ . When the R47252A is not used for a long term, it must be stored in dry place without direct sunlight (the board is inserted into the conductive case attached). Please note that the range of temperatures under which the floppy disk is +10  $^{\circ}$  to 60  $^{\circ}$ .

6.2 Transportation for R47252A

# 6.2 Transportation for R47252A

To transport the R47252A, use firstly-delivered packing material. If packing material is already lost, pack the R47252A as follows.

#### Procedure

- (1) Cover the R47252A with vinyl.
- ② Use the cardboard case whose width is 5 mm or more, and set cushioning material more than 50 mm inside to fix the R47252A.
- 3 After covering the R47252A, insert accessories, re-insert cushioning material, close the cardboard, and fix the board by packing string.

#### 7.1 Input Specification

#### 7. SPECIFICATION

#### 7.1 Input Specification

Applicable microprocessor

: Motorola's MC68000L, MC68000CL, MC68000AL, MC68000G, MC68000CG (4/6/8/10/12.5 MHz), MC68010L, MC68010CL, MC68010G (8/10/12.5 MHz)

Tomson's EF68000C, EF68000 CV (16 MHz) and equivalent

Microprocessor clock frequency

: As specified in system under test (SUT).

Input current

: -200  $\mu A$  max. (low level) 20  $\mu A$  max. (high level)

Microprocessor status display

: Displayed by LED on the microprocessor probe. CLK, RESET, INTR, DTACK/VPA, BEEP/HALT, and BR/BGACK

Personality kit operation mode

: 1. Bus sample mode ; Fetches data on 68000/68010 bus.
2. Queue sample mode; Fetches data on the bus at timing

synchronized with the internal queue of 68000/68010.

Logical polarity

: + or -

Input group: Defined by collecting data enter channel.

Input group name

: Six alphanumeric characters or less

Input group number

: Up to six groups. Three groups are already defined (ADRS, DATA, and STATUS).

7.2 Display Specification

# 7.2 Display Specification

Display data source

: Acquisition memory, reference memory, file

Display item

: Up to eight items

Input group display order

: The input group can be displayed at proper order by selecting the enter group name.

The same input group can be duplicated. The specific input group displayed can be erased.

Display system

: Bus sample mode is displayed.
The S-by-S is displayed in the queue sample mode and the PACKED is displayed.
A state is displayed by one of binary, octal, decimal, hexadecimal, symbol, code, ASCII code, or 68000/68010 mnemonic (only data).

Transfer between memory

: Display data is transferred to reference memory. Data for reference memory is displayed. Data for acquisition memory is displayed.

Data scroll: Vertical scroll is enabled by scroll knob. The vertical scroll per page is enabled by page scroll key.

Special display

: Trigger is displayed for trigger. The memory division boundary is displayed between trace windows.

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